

# BLP8G27-10

Power LDMOS transistor

Rev. 1 — 24 August 2015

Product data sheet

## 1. Product profile

### 1.1 General description

10 W plastic LDMOS power transistor for base station applications at frequencies from 700 MHz to 2700 MHz.

**Table 1. Application performance (multiple frequencies)**

Typical RF performance at  $T_{case} = 25\text{ }^{\circ}\text{C}$ ;  $I_{DQ} = 110\text{ mA}$ ; in a class-AB application circuit.

Test signal	f	$I_{DQ}$	$V_{DS}$	$P_{L(AV)}$	$G_p$	$\eta_D$	$ACPR_{5M}$
	(MHz)	(mA)	(V)	(dBm)	(dB)	(%)	(dBc)
Pulsed CW	2700	110	28	33	17	19	-
2-carrier W-CDMA [1]	2700	110	28	33	17	22	-47.3

[1] Test signal: 2-carrier W-CDMA; carrier spacing = 5 MHz. PAR = 8.4 dB at 0.01 % probability on CCDF.

### 1.2 Features and benefits

- High efficiency
- Excellent ruggedness
- Designed for broadband operation
- Excellent thermal stability
- High power gain
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

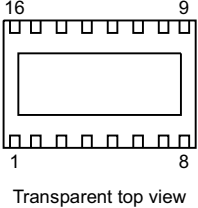
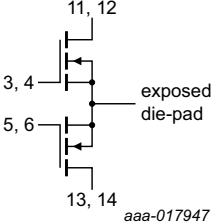
### 1.3 Applications

- CDMA
- W-CDMA
- GSM EDGE
- MC-GSM
- LTE
- WiMAX



## 2. Pinning information

**Table 2. Pinning**

Pin	Description	Simplified outline	Graphic symbol <a href="#">[1]</a>
1, 2, 7, 8, 9, 10, 15, 16	n.c.	 <p>Transparent top view</p>	 <p>aaa-017947</p>
3, 4, 5, 6	gate		
11, 12, 13, 14	drain		
exposed die-pad	source <a href="#">[2]</a>		

[1] To be used in single ended applications only.

[2] Connected to flange.

## 3. Ordering information

**Table 3. Ordering information**

Type number	Package		
	Name	Description	Version
BLP8G27-10	HVSON16	plastic thermal enhanced very thin small outline package; no leads;16 terminals; body 4 × 6 × 0.85 mm	SOT1371-1

## 4. Limiting values

**Table 4. Limiting values**

*In accordance with the Absolute Maximum Rating System (IEC 60134).*

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage		-	65	V
$V_{GS}$	gate-source voltage		-0.5	+13	V
$T_{stg}$	storage temperature		-65	+150	°C
$T_j$	junction temperature		-	225	°C

## 5. Thermal characteristics

**Table 5. Thermal characteristics**

Symbol	Parameter	Conditions	Typ	Unit
$R_{th(j-c)}$	thermal resistance from junction to case	$T_{case} = 80\text{ °C}; P_L = 2\text{ W}$	3.2	K/W

## 6. Characteristics

**Table 6. DC characteristics**

$T_j = 25\text{ }^\circ\text{C}$ ; unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0\text{ V}$ ; $I_D = 0.18\text{ mA}$	65	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10\text{ V}$ ; $I_D = 18\text{ mA}$	1.5	1.9	2.3	V
$I_{DSS}$	drain leakage current	$V_{GS} = 0\text{ V}$ ; $V_{DS} = 28\text{ V}$	-1.4	-	+1.4	$\mu\text{A}$
$I_{DSX}$	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75\text{ V}$	-	3.2	-	A
$I_{GSS}$	gate leakage current	$V_{GS} = 11\text{ V}$ ; $V_{DS} = 0\text{ V}$	-	-	140	nA
$g_{fs}$	forward transconductance	$V_{DS} = 10\text{ V}$ ; $I_D = 18\text{ mA}$	-	160	-	mS
$R_{DS(on)}$	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75\text{ V}$ ; $V_{DS} = 10\text{ V}$ ; $I_D = 630\text{ mA}$	-	1000	-	$\text{m}\Omega$

**Table 7. RF characteristics**

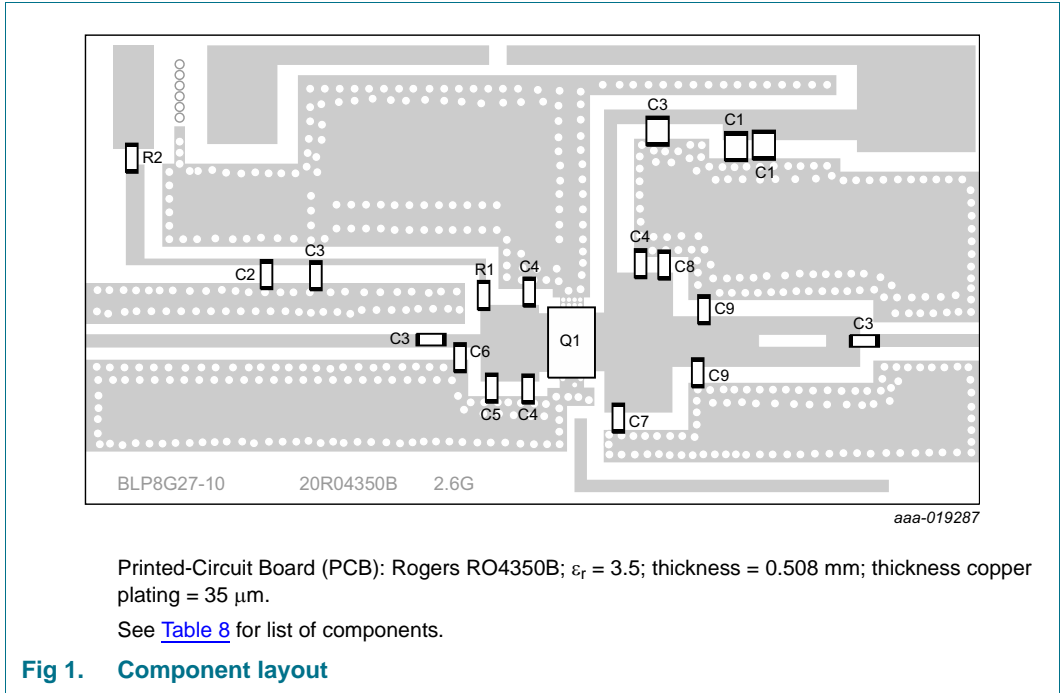
A derivative functional RF test is performed in production. The performance as mentioned below is verified by design and characterization in an NXP class-AB application board.

Test signal: pulsed CW;  $\delta = 10\%$ ;  $t_p = 100\text{ }\mu\text{s}$ ;  $V_{DS} = 28\text{ V}$ ;  $I_{Dq} = 110\text{ mA}$ ;  $T_{case} = 25\text{ }^\circ\text{C}$ ;  $f = 2140\text{ MHz}$

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$G_p$	power gain	$P_{L(AV)} = 2\text{ W}$	16	17	-	dB
$\eta_D$	drain efficiency	$P_{L(AV)} = 2\text{ W}$	17	19	-	%
$P_{L(1dB)}$	output power at 1 dB gain compression		10	-	-	W

**7. Application information**

**7.1 Application circuit**



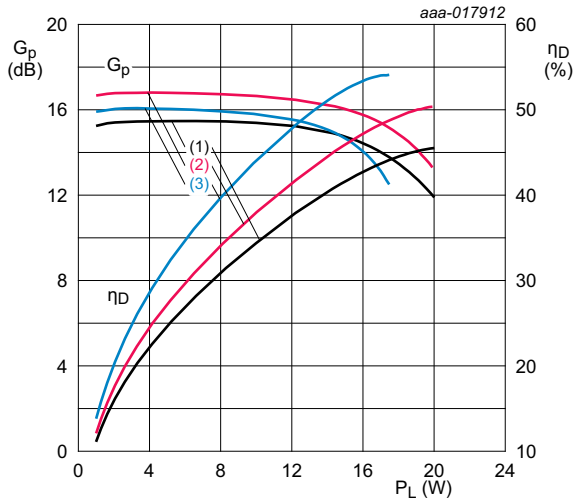
**Table 8. List of components**

See [Figure 1](#) for component layout.

Component	Description	Value	Remarks
C1	multilayer ceramic chip capacitor	10 $\mu\text{F}$	Murata
C2	multilayer ceramic chip capacitor	1 $\mu\text{F}$	Murata
C3	multilayer ceramic chip capacitor	15 pF	ATC 600F
C4	multilayer ceramic chip capacitor	2 pF	ATC 600F
C5	multilayer ceramic chip capacitor	1.3 pF	ATC 600F
C6	multilayer ceramic chip capacitor	0.5 pF	ATC 600F
C7	multilayer ceramic chip capacitor	1.8 pF	ATC 600F
C8	multilayer ceramic chip capacitor	0.3 pF	ATC 600F
C9	multilayer ceramic chip capacitor	0.9 pF	ATC 600F
R1	chip resistor	5.1 $\Omega$	
R2	chip resistor	0 $\Omega$	
Q1	transistor	-	BLP8G27-10

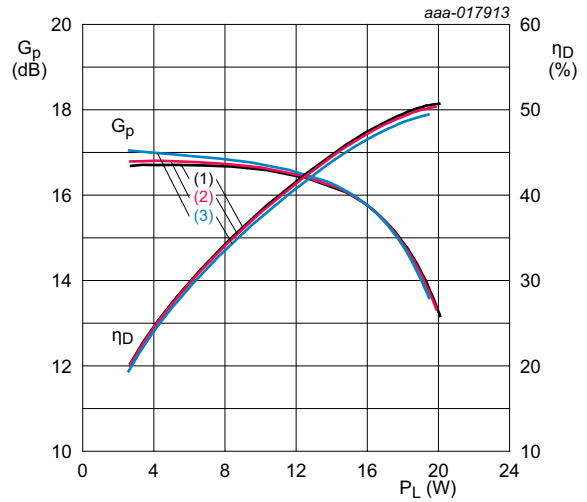
**7.2 Graphical data**

**7.2.1 Pulsed CW**



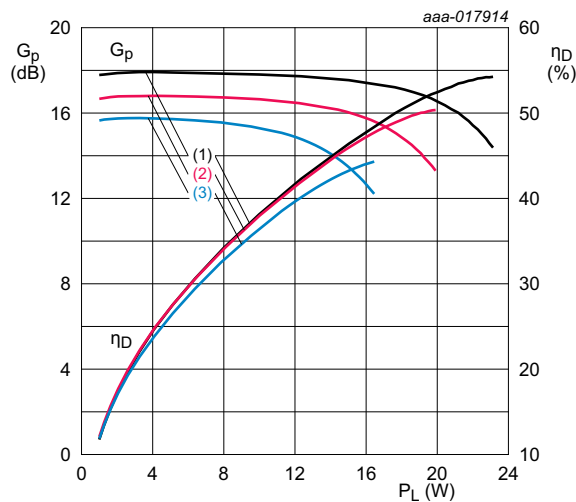
$V_{DS} = 28\text{ V}$ ;  $I_{Dq} = 110\text{ mA}$ ;  $T_{case} = 25\text{ }^\circ\text{C}$ ;  $\delta = 10\%$ ;  $t_p = 100\text{ }\mu\text{s}$ .  
 (1)  $f = 2500\text{ MHz}$   
 (2)  $f = 2600\text{ MHz}$   
 (3)  $f = 2700\text{ MHz}$

**Fig 2. Power gain and drain efficiency as function of output power; typical values**



$V_{DS} = 28\text{ V}$ ;  $T_{case} = 25\text{ }^\circ\text{C}$ ;  $f = 2600\text{ MHz}$ ;  $\delta = 10\%$ ;  $t_p = 100\text{ }\mu\text{s}$ .  
 (1)  $I_{Dq} = 90\text{ mA}$   
 (2)  $I_{Dq} = 110\text{ mA}$   
 (3)  $I_{Dq} = 130\text{ mA}$

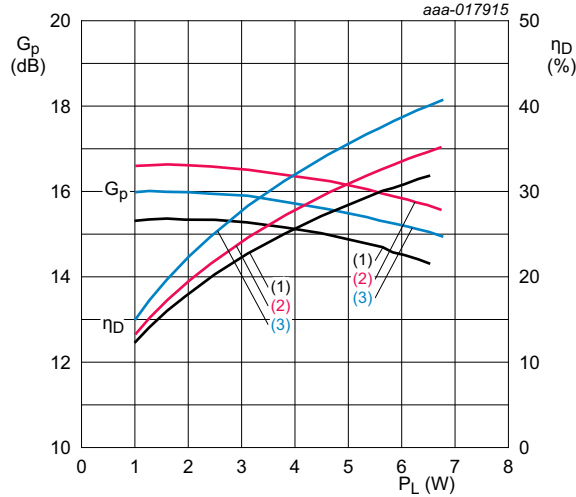
**Fig 3. Power gain and drain efficiency as function of output power; typical values**



$V_{DS} = 28\text{ V}$ ;  $I_{Dq} = 110\text{ mA}$ ;  $f = 2600\text{ MHz}$ ;  $\delta = 10\%$ ;  $t_p = 100\text{ }\mu\text{s}$ .  
 (1)  $T_{case} = -37\text{ }^\circ\text{C}$   
 (2)  $T_{case} = +25\text{ }^\circ\text{C}$   
 (3)  $T_{case} = +85\text{ }^\circ\text{C}$

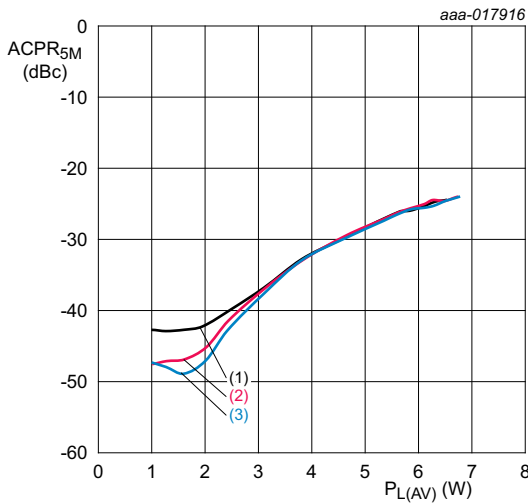
**Fig 4. Power gain and drain efficiency as function of output power; typical values**

7.2.2 2-Carrier W-CDMA



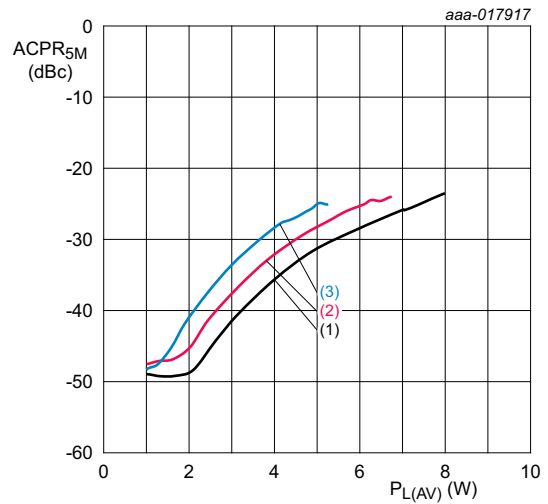
$V_{DS} = 28\text{ V}$ ;  $I_{Dq} = 110\text{ mA}$ ;  $T_{case} = 25\text{ }^{\circ}\text{C}$ ; carrier spacing = 5 MHz; 46 % clipping; PAR = 8.4 dB at 0.01 % probability on CCDF.  
 (1)  $f = 2500\text{ MHz}$   
 (2)  $f = 2600\text{ MHz}$   
 (3)  $f = 2700\text{ MHz}$

Fig 5. Power gain and drain efficiency as function of output power; typical values



$V_{DS} = 28\text{ V}$ ;  $I_{Dq} = 110\text{ mA}$ ;  $T_{case} = 25\text{ }^{\circ}\text{C}$ ;  
 carrier spacing = 5 MHz; 46 % clipping; PAR = 8.4 dB at 0.01 % probability on CCDF.  
 (1)  $f = 2500\text{ MHz}$   
 (2)  $f = 2600\text{ MHz}$   
 (3)  $f = 2700\text{ MHz}$

Fig 6. Adjacent channel power ratio (5 MHz) as a function of average output power; typical values



$V_{DS} = 28\text{ V}$ ;  $I_{Dq} = 110\text{ mA}$ ;  $f = 2600\text{ MHz}$ ;  
 carrier spacing = 5 MHz; 46 % clipping; PAR = 8.4 dB at 0.01 % probability on CCDF.  
 (1)  $T_{case} = -37\text{ }^{\circ}\text{C}$   
 (2)  $T_{case} = +25\text{ }^{\circ}\text{C}$   
 (3)  $T_{case} = +85\text{ }^{\circ}\text{C}$

Fig 7. Adjacent channel power ratio (5 MHz) as a function of average output power; typical values

## 8. Test information

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### 8.1 Ruggedness in class-AB operation

The BLP8G27-10 is capable of withstanding a load mismatch corresponding to  $V_{SWR} = 10 : 1$  through all phases under the following conditions:  $V_{DS} = 28 \text{ V}$ ;  $I_{Dq} = 110 \text{ mA}$ ;  $P_L = 2 \text{ W}$ ; frequency from 700 MHz to 2700 MHz.

9. Package outline

HVSON16: plastic thermal enhanced very thin small outline package; no leads; 16 terminals; body 4 x 6 x 0.85 mm

SOT1371-1

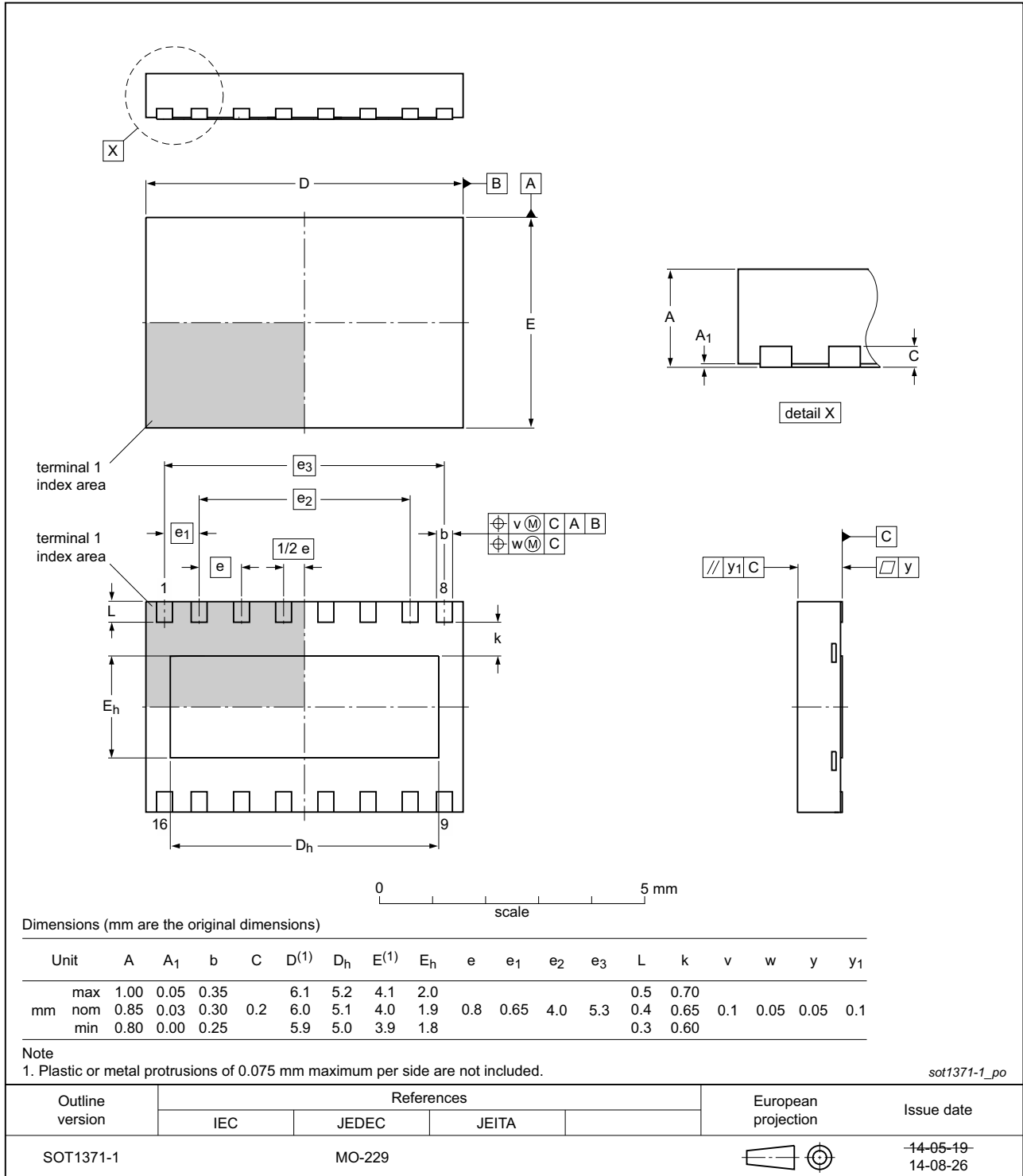


Fig 8. Package outline SOT1371-1 (HVSON16)



## 10. Handling information

### CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the *ANSI/ESD S20.20*, *IEC/ST 61340-5*, *JESD625-A* or equivalent standards.

## 11. Abbreviations

Table 9. Abbreviations

Acronym	Description
CCDF	Complementary Cumulative Distribution Function
CDMA	Code Division Multiple Access
CW	Continuous Wave
EDGE	Enhanced Data rates for GSM Evolution
ESD	ElectroStatic Discharge
GSM	Global System for Mobile Communication
LDMOS	Laterally Diffused Metal-Oxide Semiconductor
LTE	Long Term Evolution
MC-GSM	Multi Carrier GSM
PAR	Peak-to-Average Ratio
VSWR	Voltage Standing-Wave Ratio
W-CDMA	Wideband Code Division Multiple Access
WiMAX	Worldwide Interoperability for Microwave Access

## 12. Revision history

Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLP8G27-10 v.1	20150824	Product data sheet	-	-

## 13. Legal information

### 13.1 Data sheet status

Document status <sup>[1][2]</sup>	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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